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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/623,679	07/22/2003	Koji Nozaki	030891	5083
38834	7590 01/25/2005		EXAMINER	
WESTERMA	AN, HATTORI, DAN	WALKE, AMANDA C		
1250 CONNECTICUT AVENUE, NW SUITE 700 WASHINGTON, DC 20036				
			ART UNIT	PAPER NUMBER
			1752	
			DATE MAILED: 01/25/2005	

Please find below and/or attached an Office communication concerning this application or proceeding.

		m/
	Application No.	Applicant(s)
	10/623,679	NOZAKI ET AL.
Office Action Summary	Examiner	Art Unit
	Amanda C Walke	1752
The MAILING DATE of this communication app Period for Reply	ears on the cover sheet with the o	orrespondence address
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION.  - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication.  - If the period for reply specified above is less than thirty (30) days, a reply - If NO period for reply is specified above, the maximum statutory period v - Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may a reply be ting within the statutory minimum of thirty (30) day will apply and will expire SIX (6) MONTHS from a cause the application to become ABANDONE	nely filed  vs will be considered timely. I the mailing date of this communication. D (35 U.S.C. § 133).
Status	•	
<ul> <li>1) Responsive to communication(s) filed on <u>03 Not</u></li> <li>2a) This action is <b>FINAL</b>. 2b) This</li> <li>3) Since this application is in condition for allower closed in accordance with the practice under Exercise.</li> </ul>	action is non-final. nce except for formal matters, pro	
Disposition of Claims		
4) ☐ Claim(s) 1-28 is/are pending in the application. 4a) Of the above claim(s) is/are withdraw 5) ☐ Claim(s) 23-28 is/are allowed. 6) ☐ Claim(s) 1-22 is/are rejected. 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and/or	vn from consideration.	
9) The specification is objected to by the Examine	r.	
10)☐ The drawing(s) filed on is/are: a)☐ acc	epted or b) objected to by the	Examiner.
Applicant may not request that any objection to the		
Replacement drawing sheet(s) including the correct 11) The oath or declaration is objected to by the Ex	•	•
Priority under 35 U.S.C. § 119		
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of:  1. Certified copies of the priority documents 2. Certified copies of the priority documents 3. Copies of the certified copies of the priority documents application from the International Bureau	s have been received. s have been received in Applicati rity documents have been receive u (PCT Rule 17.2(a)).	ion No ed in this National Stage
* See the attached detailed Office action for a list	or the certified copies not receive	:u.
Attachment(s)		
1) Notice of References Cited (PTO-892)	4) Interview Summary	
<ol> <li>Notice of Draftsperson's Patent Drawing Review (PTO-948)</li> <li>Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)         Paper No(s)/Mail Date     </li> </ol>	Paper No(s)/Mail D. 5) Notice of Informal F 6) Other:	ate Patent Application (PTO-152)

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#### **DETAILED ACTION**

## Claim Rejections - 35 USC § 103

1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

- (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 2. Claims 1-8, and 14-22 are rejected under 35 U.S.C. 103(a) as being unpatentable over Yasuda et al (JP 2001-033984 in view of its English language translation).

Yasuda et al disclose a negative resist material to be coated onto a substrate, exposed, then developed to form a pattern. The resist comprises a resin (novolac, polyvinyl ether, polyvinyl acetal, etc.) meeting the instant claim limitations, a crosslinking agent (preferably melamine), an organic solvent meeting the instant claim limitations, and optionally a surfactant ([0036], [0048]). The solvent may be anionic, cationic, nonionic, amphoteric, ethyleneoxide, fatty acid amides, fatty acid esters, quarternary ammonium salts, and/ or betaine. The process of forming a pattern includes employing a photomask and developing the resist optionally with pure water ([0037], [0041], [0086]).

Given the teachings of the reference, it would have been obvious to one of ordinary skill in the art to prepare the material of Yasuda et al choosing to add any of the disclosed surfactants with reasonable expectation of achieving a material able to form an accurate fine pattern.

3. Claims 9-13 are rejected under 35 U.S.C. 103(a) as being unpatentable over Yasuda et al in view of Sato et al (5,955,241).

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Yasuda et al has been discussed above, but fails to teach or suggest the addition of a water soluble aromatic compound.

Sato et al disclose a chemical-amplification-type negative resist composition and a method for forming a negative resist pattern using the same. The chemical-amplification-type negative resist composition comprises an alkali-soluble resin, an acid-generating agent, and a compound capable of causing crosslinking reaction in the presence of an acid.

The reference further teaches "Additionally, the chemical-amplification-type negative resist composition of the present invention may further contain a light-absorbing ingredient.

Examples of compounds which can be used as the light-absorbing ingredient include naphthoquinone-1,2-diazide-5-sulfonic esters of polyphenols such as 1-[1-(4-hydroxyphenyl)isopropyl]-4-[1,1-bis(4-hydroxyphenyl)ethyl]benzene and bis(4-hydroxy-3,5-dimethylphenyl)-3,4-dihydroxyphenylmethane; benzophenone; 2,2',4,4'-tetrahydroxybenzophenone; 2,3,3',4,4',5'-hexahydroxybenzophenone; 4-dimethylamino-2',4'-dihydroxybenzophenone; 5-amino-3-methyl-1-phenyl-4-(4-hydroxyphenylazo)pyrazole; 4-dimethylamino-4'-hydroxyazobenzene; 4-diethylamino-4'-ethoxyazobenzene; 4-diethylaminoazobenzene; and curcumine.

The addition of such a light-absorbing ingredient is effective in improvement of sensitivity and definition, and the resulting resist pattern does not exhibit a wavy sectional shape but exhibits a suitable rectangular sectional shape. "

Given the teachings of Sato et al, it would have been obvious to one of ordinary skill in the art to prepare the material of Yasuda et al choosing to add a light absorbing compound of Art Unit: 1752

Sato et al to achieve an increase in the sensitivity of the material, with reasonable expectation of achieving a material able to form an accurate fine pattern.

## Allowable Subject Matter

4. The following is a statement of reasons for the indication of allowable subject matter:

Claims 23-28 are indicated as containing allowable subject matter. The Yasuda reference (prior art of record), fails to teach or suggest to one of ordinary skill in the art to prepare a pattern by employing a layer of resist and coating a second layer (resist thickening layer) as claimed.

#### Response to Arguments

5. Applicant's arguments filed 11/3/2004 have been fully considered but they are not persuasive.

Applicant has argued that the invention disclosed by Yasuda et al. is generally directed to a method wherein an organic layer is formed on a negative resist pattens, and then the organic layer on the resist pattern is developed by an alkali developer to thereby reduce the size of the resist pattern. Thus, the effect of the material of Yasuda et al. is opposed to that of the present invention. In the present invention, the material of the claim 1 is formed on a resist material layer to thicken the resist material. Also, an organic film of Yasuda et al. is formed on a negative resist pattern (claim 1), but the composition for the organic film does not include any crosslinking agent, which is different from the material of the present invention. This means that the invention of Yasuda et al. is not a resist pattern thickening material. Please note that melamine' as a crosslinking agent is disclosed by Yasuda et al, but it is included in the resist material, not in the

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organic film. See paragraphs (0036) and (0048j. The organic film of Yasuda et al. is heated and the base diffuses from the organic film to the first negative resist pattern, solubilizing the first negative resist pattern into an exfoliation liquid, as disclosed in paragraph (00432. Therefore, any crosslinking agent should not be included in the organic film of Yasuda et al. The examiner points out that the claims are drawn to a material comprising a resin, a crosslinking agent, and at least one of a cationic surfactant, an amphoteric surfactant, and a non-ionic surfactant selected from an alkoxylate surfactant, a fatty acid ester surfactant, an amide surfactant, an alcohol surfactant, and an ethylene diamine surfactant. As admitted by applicant, the negative resist material of Yasuda does comprise the claimed components for the thickening material, thus it is the position of the examiner that this layer is taught and would function in a similar manner to the instantly claimed material.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Amanda C Walke whose telephone number is 571-272-1337. The examiner can normally be reached on M-R 5:30-4.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Cynthia Kelly can be reached on 571-272-1526. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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Amanda C Walke

Examiner

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ACW January 24, 2005